



Beam Condition Monitor for the CMS

BCM Group

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Beam Condition Monitor for CMS

Purpose

- The Beam Condition Monitor (BCM) has to provide online radiation monitoring within the CMS
- BCM forms part of the radiation monitoring system for equipment safety and radiation level/beam monitoring
- The BCM should be in addition to the LHC machine protection system and Beam Loss Monitors

BCM Issues

- Allows protection of equipment during instabilities/accidents
- Provides fast feedback to the machine for optimization of beam conditions
- Provides fast feedback to the machine for detection of adverse beam conditions
- Monitors the instantaneous dose during operation
- Provides input into LHC beam abort system (1 input/ experiment)

Accident Scenarios



- •Sensors under investigation: Polycrystalline Diamond
 - Fast signal response
 - Radiation hardness
 - Minimal services required ie no cooling necessary

Evaluated using a fast extraction beam from the CERN PS at the T7 beamline (November 2003)

Beam Accidents What are the timescales

List of machine-identified equipment failures

Name	Operation Mode	Loss Location	ΔΤ	
D1 warm	Collision	Triplet/collimator	5 turns	
Damper	Injection	Arc/triplet	6 turns	
Warm quadrupoles	Any	Collimator	18 turns	
Warm orbit corrector	Collision	Triplet/collimator	55 turns	
RF	Any	Arc/triplet/septum	55 turns	
D1 warm	Injection	Arc/triplet/collimator	120 turns	

Fastest generic beam loss scenarios: ~ in 5 orbits ie ~ 500μ s the beam is off by 3 sigma, this defines the response timescale of our system.

Beam Accidents What are the timescales

After 15 turns



A MAD simulation for a D1 failure (by V. Kain) will serve us to calculate the numbers of protons that will be lost per turn. Then a Fluka simulation can give us the dose per turn that will allow us to set the timescales and the thresholds.

Conceptual BCM layout



DCS

Monitoring and control of the detector

DSS

Safeguard of experimental equipment

BCM

- Input into DSS.
- Protect subdetectors from adverse beam conditions
- Redundant of the Beam Loss Monitors of the Machine



Diamond Characterization

Measurements performed on diamonds:

• I-V curve.

First quality check of the samples, metallisations. To determine the electrical resistivity.

Collection distance vs time.

Study of the pumping. Charge collection distance at 1 V/ μm.

• Collection distance vs bias voltage.

Measurement of the charge collection distance at different electric fields. Study of the radiation damage. Study of the polarization.

• I-T curve.

Find the thermo-stimulated current peak. Number of traps. Depumping of diamonds.

Diamond Characterization



Diamond Characterization



Study of the radiation damage

Collection distance vs electrical field for an irradiated diamond:

1st irradiation of 5E14 p/cm²

2nd irradiation of 1E15 p/cm²

The hysteresis observed is due to a charge polarization effect.



Measurement of the charge collection distance - Study of the polarization

Polycrystalline diamond presents a polarization effect every time a bias voltage is applied to it.

The polarization appears any time the bias is increased.

This graphic shows the "real" values of the collection distance (after polarization) at different electrical fields, after 4 hours.



T7 Testbeam Hardware





November T7 Test beam: Fast extraction beam from the PS



Beam intensity: 8x10¹¹protons per spill Fluence: ~3x10¹⁰ protons/cm²/spill at the centre of the beam spot ~1x10⁸ protons/cm²/spill in the halo

Beam profile

90 mm



Beam Profile as measures by OSL film OSL =Optically Stimulated Luminesence

mm	0	5	10	15	20	25	30	35	40	45	50	55	60	65	70	75	80	85	90
0	0.2	0.2	0.2	0.2	0.3	0.2	0.0	0.0	0.0	0.0	0.0	0.0	0.0	0.1	0.1	0.1	0.1	0.1	0.0
5	0.2	0.2	0.2	0.3	0.3	0.3	0.1	0.3	0.4	0.8	0.7	1.0	1.0	1.4	1.3	1.2	1.0	0.1	0.1
10	0.6	0.6	0.6	0.8	0.9	0.9	0.8	0.8	1.0	1.0	1.1	1.3	1.5	2.1	2.0	2.0	1.6	0.2	0.1
15	0.6	0.6	0.6	0.8	1.1	1.1	1.3	1.1	1.4	1.6	1.8	2.3	2.6	3.5	3.0	2.9	2.7	0.2	0.1
20	0.7	0.7	0.7	1.1	1.4	1.7	1.9	2.1	2.8	3.2	4.9	5.0	7.7	9.8	12.7	10.6	6.2	0.5	0.1
25	0.7	0.9	0.9	1.0	1.5	3.1	7.4	10.3	13.1	15.6	17.6	21.5	26.7	38.9	56.7	45.0	17.7	1.2	0.1
30	0.7	0.9	0.8	1.1	2.2	7.4	18.6	28.4	28.9	39.3	45.6	48.9	70.8	82.1	100	87.8	36.5	4.3	0.2
35	0.7	0.8	0.9	1.1	2.7	6.1	17.4	25.1	28.5	94.4	27.7	42.4	42.2	61.1	58.1	69.2	28.1	6.1	0.2
40	0.6	0.7	0.8	1.1	2.2	4.1	6.6	8.1	8.5	8.6	10.3	13.5	18.7	26.7	36.0	28.3	10.5	3.4	0.2
45	0.6	0.7	0.7	0.8	1.1	1.9	2.2	1.7	1.7	2.7	3.1	4.3	5.8	7.6	8.1	5.7	4.0	2.4	0.2
50	0.7	0.6	0.7	0.9	0.8	1.0	1.2	1.1	1.3	1.5	1.6	2.2	2.2	2.6	3.1	2.6	2.3	1.8	0.1
55	0.4	0.5	0.6	0.7	0.8	0.8	0.8	0.7	0.8	1.1	1.0	1.1	0.7	0.6	0.4	0.4	0.3	0.2	0.1

Film exposure of the beam after 40 bunches



Relative fluence levels

Position 0 = 1.0Position $1 \sim 0.4$ Position $2 \sim 0.2$ Position $3 \sim 0.01$

Dosimetry measurements

Beamspot Dosimetry

Used ²⁴Na for dosimetry on aluminum placed in the beam

Dosimetry done by Maurice Glaser and Federico Ravotti

<u>Result</u> Fluence at beam "centre" = 2.8x10¹⁰ protons/cm² ± 10%

<u>Mapping of beam spot</u> Consistency between the different films, the OSL, and the aluminum



Dosimetry Results from Grid of Aluminum samples: Relative variation %											
0.0	3.3	10.2	13.8	16.5	27.7	33.1	0.0	0.0			
1.3	5.3	11.9	19.1	31.8	74.2	100.0	63.0	0.0			
0.0	0.0	0.0	0.0	3.4	8.0	6.2	0.0	0.0			

Single shots



Almost identical to PS beam profile

Single pulses from diamond

- Bias on Diamond = +1 V/ μ m
- Readout of signal:
 - 16m of cable
 - no electronics
 - 20dB attenuation on

signal cable (factor 10)



Single shots: Details



Diamond Collection Distance

Signals from sensors are large

- V_max (CDS116) = 88 volts => 1.76 Amps into a 50 Ohm load
- V_max (CDS126) = 61 volts => 1.22 Amps into a 50 Ohm load

Time response

Fit Gaussian to leading edge of pulses σ (CDS126) =10.5 ± 0.5 ns σ (CDS116) = 9.0 ± 0.3 ns

Comparable to $\sigma(PS)=10.5$ ns with ~6% distortion from the signal cable

=> No problem with extracting timing structure from sensors on 16 m coax cable

Multiple Bunches





C1 acts as a reservoir capacitor =>The larger the value the longer the bias field on the can be maintained.

C1(CDS126)=15 nF

C1 is sufficiently large to maintain bias across the diamond for the 8 bunches.

C1R1 time constant ~15 ms \Rightarrow recharge of C1 is slow compared to bunch structure



Multiple Bunches





- An automatic setup for measuring diamond characteristics has been developed.
- This setup allows detailed studies of diamond polarization effects.
- Diamonds are able to withstand intense beam.



- Finish analyzing the data that we have from the November testbeam:
 - Data taken is for the "worst case" scenario
- Build a prototype BCM (sensors+ electronics + decision logic)
 - Reduce signal to noise so to clearly see MIPs
- Continue with the characterization of diamonds
- May 04: Return to the East Hall for dedicated fast extraction beam
 - Intensity: 10³ to 10⁶particle/cm²
 - Test prototype electronics
 - Evaluate BCM threshold-response time